

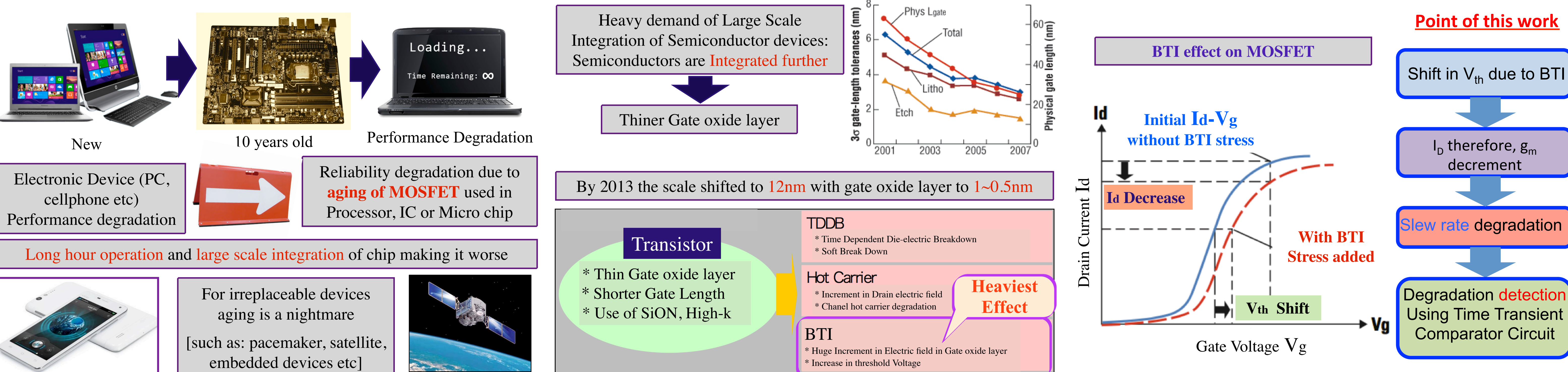
# Bias Temperature Instability Detection of Integrated Circuit

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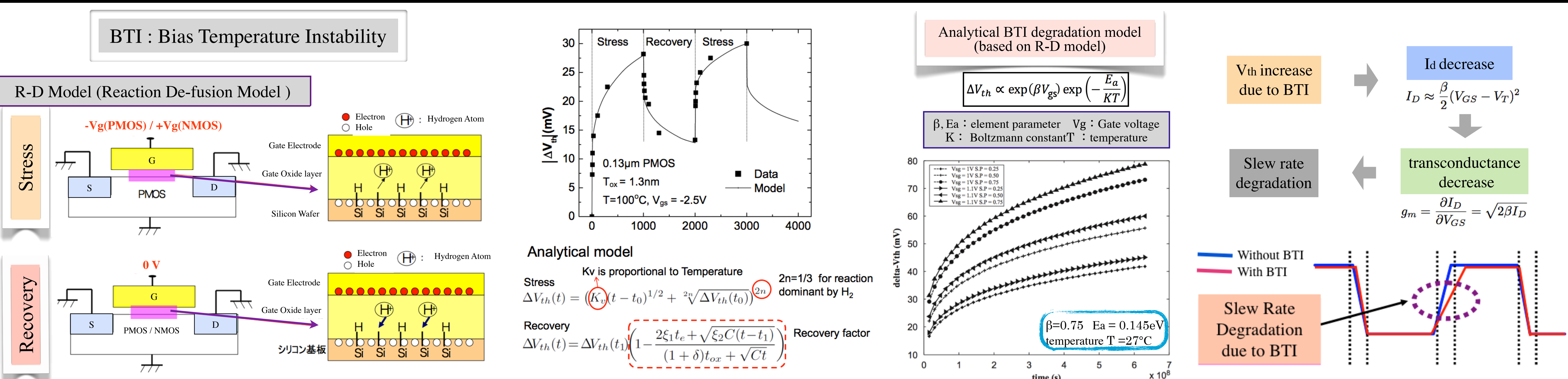
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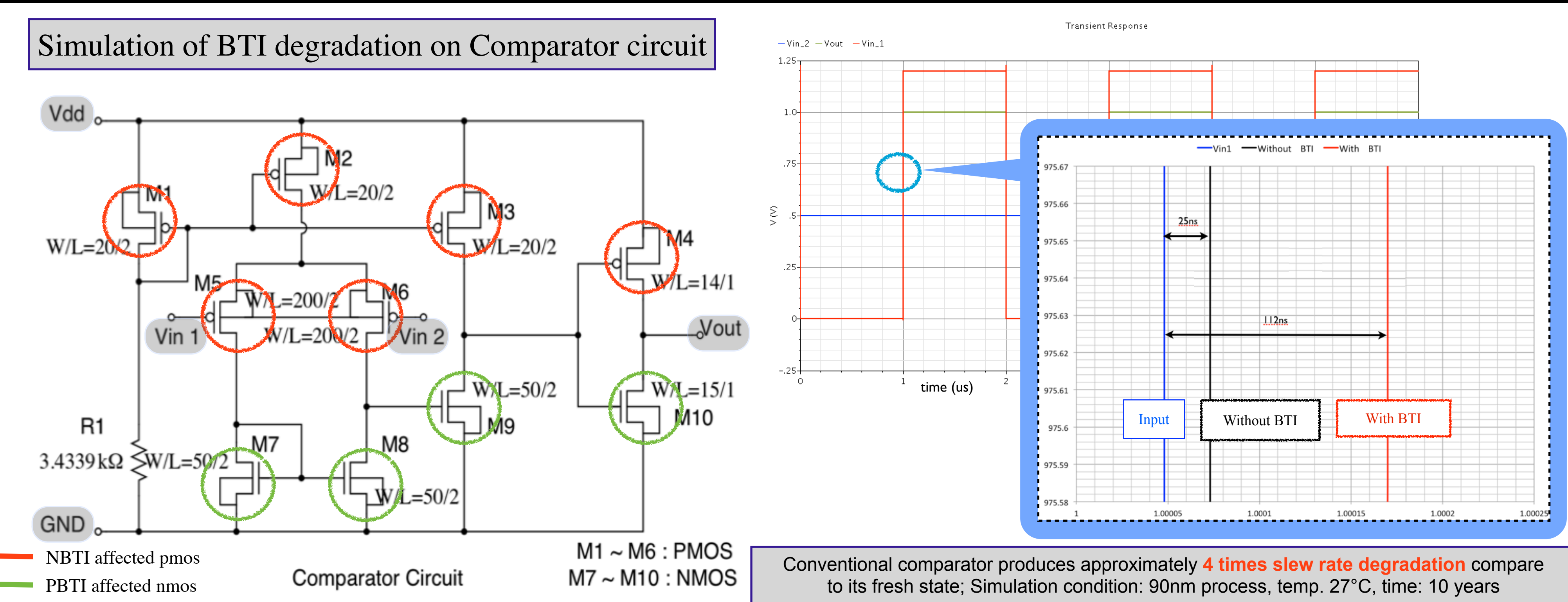
## 1. Background:



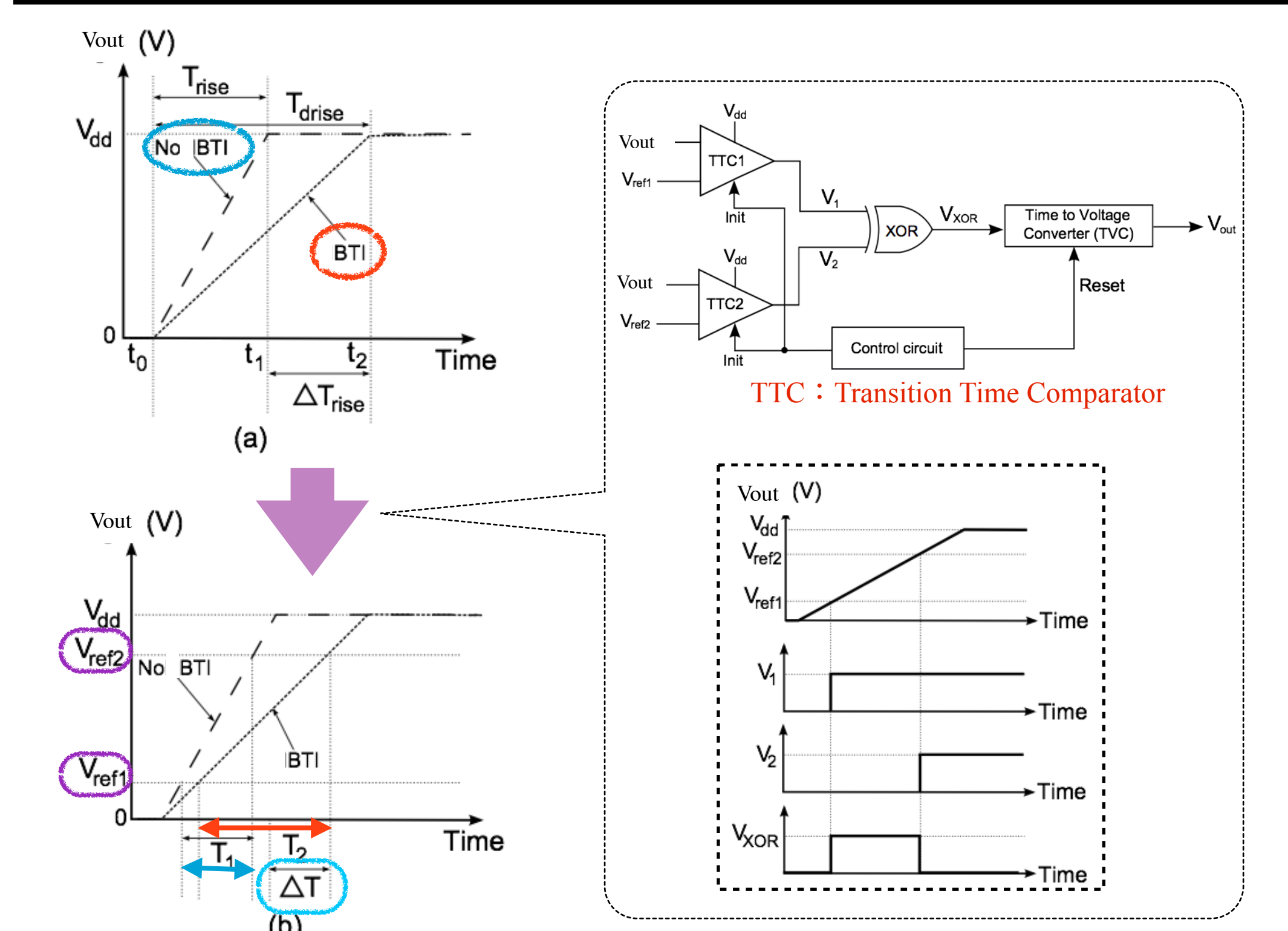
## 2. BTI Effect on Analog Circuit



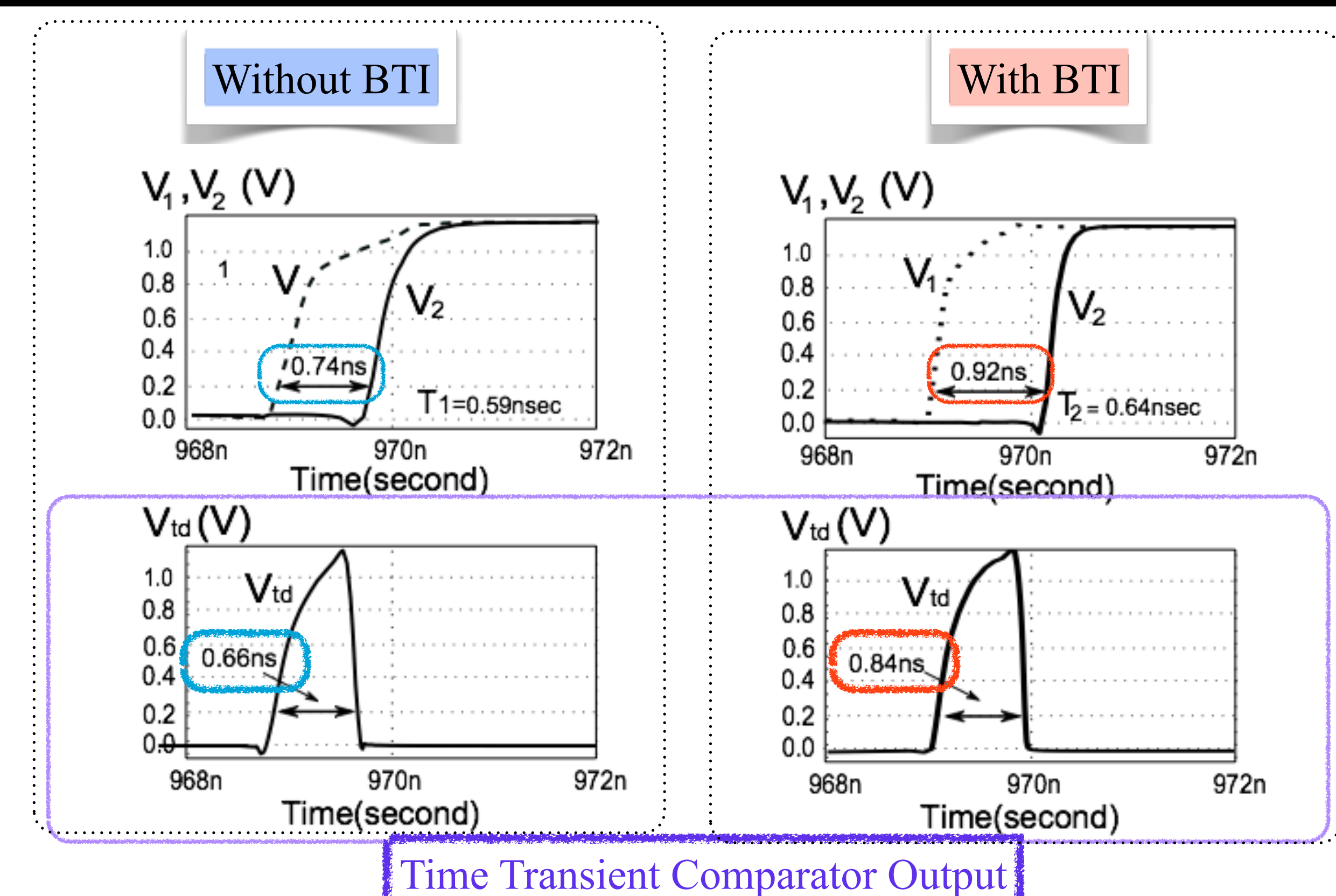
## 3. Simulation Result



## 4. Proposed Detection method



## 5. Experimental Result



## 6. Conclusion

